

# 74AVC20T245-Q100

20-bit dual supply translating transceiver with configurable voltage translation; 3-state

Rev. 1 — 7 April 2016

Product data sheet

## 1. General description

The 74AVC20T245-Q100 is a 20 bit, dual supply transceiver that enables bidirectional voltage level translation. The device can be used as two 10-bit transceivers or as a single 20-bit transceiver. It features four 10-bit input-output ports (1An, 1Bn, 2An, 2Bn) and two output enable inputs (nOE). It has two direction inputs (nDIR) and dual supplies ( $V_{CC(A)}$  and  $V_{CC(B)}$ ).  $V_{CC(A)}$  and  $V_{CC(B)}$  can be independently supplied at any voltage between 0.8 V and 3.6 V. It makes the device suitable for bidirectional voltage level translation between any of the low voltage nodes: 0.8 V, 1.2 V, 1.5 V, 1.8 V, 2.5 V and 3.3 V. The 1An and 2An ports, nOE and (nDIR) are referenced to  $V_{CC(A)}$ , the 1Bn and 2Bn ports are referenced to  $V_{CC(B)}$ . A HIGH on a 1DIR allows transmission from 1An to 1Bn and a LOW on 1DIR allows transmission from 1Bn to 1An. A HIGH on nOE causes the outputs to assume a HIGH impedance OFF-state.

The device is fully specified for partial power-down applications using  $I_{OFF}$ . The  $I_{OFF}$  circuitry disables the output, preventing any damaging backflow current through the device when it is powered down. In suspend mode when either  $V_{CC(A)}$  or  $V_{CC(B)}$  are at GND level, all output ports assume a high impedance OFF-state.

This product has been qualified to the Automotive Electronics Council (AEC) standard Q100 (Grade 1) and is suitable for use in automotive applications.

## 2. Features and benefits

- Automotive product qualification in accordance with AEC-Q100 (Grade 1)
  - ◆ Specified from -40 °C to +85 °C and from -40 °C to +125 °C
- Wide supply voltage range:
  - ◆  $V_{CC(A)}$ : 0.8 V to 3.6 V
  - ◆  $V_{CC(B)}$ : 0.8 V to 3.6 V
- Complies with JEDEC standards:
  - ◆ JESD8-12 (0.8 V to 1.3 V)
  - ◆ JESD8-11 (0.9 V to 1.65 V)
  - ◆ JESD8-7 (1.2 V to 1.95 V)
  - ◆ JESD8-5 (1.8 V to 2.7 V)
  - ◆ JESD8-B (2.7 V to 3.6 V)
- ESD protection:
  - ◆ MIL-STD-883, method 3015 Class 3B exceeds 8000 V
  - ◆ HBM JESD22-A114E Class 3B exceeds 8000 V
  - ◆ MM JESD22-A115-A exceeds 200 V ( $C = 200 \text{ PF}$ ,  $R = 0 \Omega$ )
- Maximum data rates:



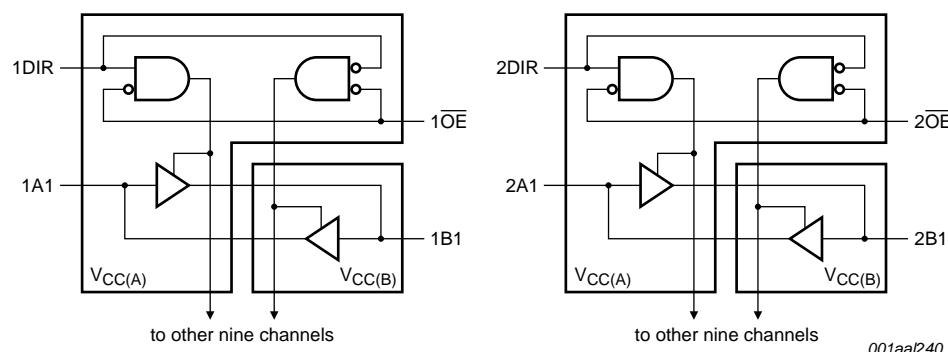
- ◆ 380 Mbit/s ( $\geq 1.8$  V to 3.3 V translation)
- ◆ 260 Mbit/s ( $\geq 1.1$  V to 3.3 V translation)
- ◆ 260 Mbit/s ( $\geq 1.1$  V to 2.5 V translation)
- ◆ 210 Mbit/s ( $\geq 1.1$  V to 1.8 V translation)
- ◆ 120 Mbit/s ( $\geq 1.1$  V to 1.5 V translation)
- ◆ 100 Mbit/s ( $\geq 1.1$  V to 1.2 V translation)
- Suspend mode
- Latch-up performance exceeds 100 mA per JESD 78 Class II
- Inputs accept voltages up to 3.6 V
- $I_{OFF}$  circuitry provides partial Power-down mode operation

### 3. Ordering information

**Table 1. Ordering information**

Type number	Package			
	Temperature range	Name	Description	Version
74AVC20T245DGG-Q100	-40 °C to +125 °C	TSSOP56	plastic thin shrink small outline package; 56 leads; body width 6.1 mm	SOT364-1

### 4. Functional diagram



**Fig 1. Logic diagram**

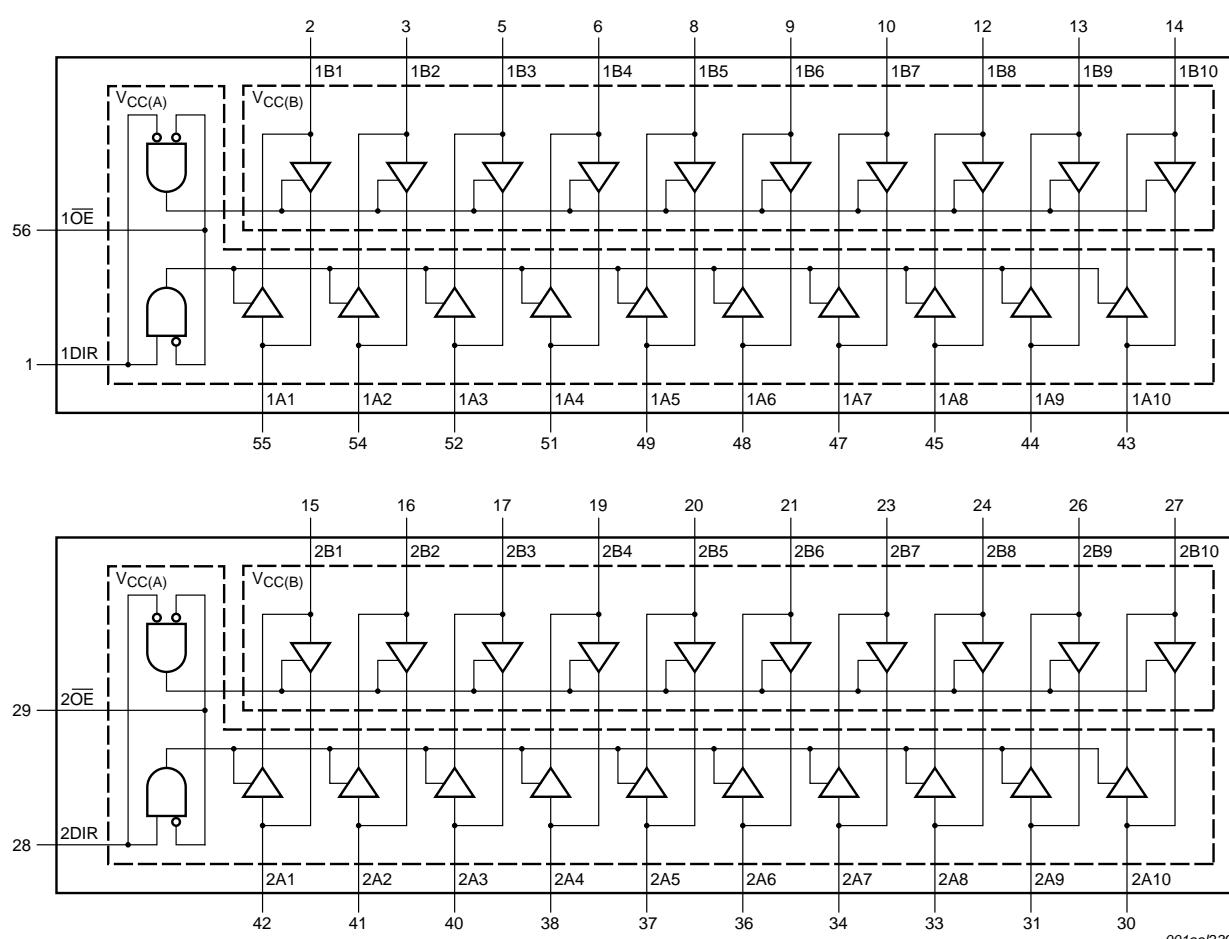


Fig 2. Logic symbol

## 5. Pinning information

### 5.1 Pinning

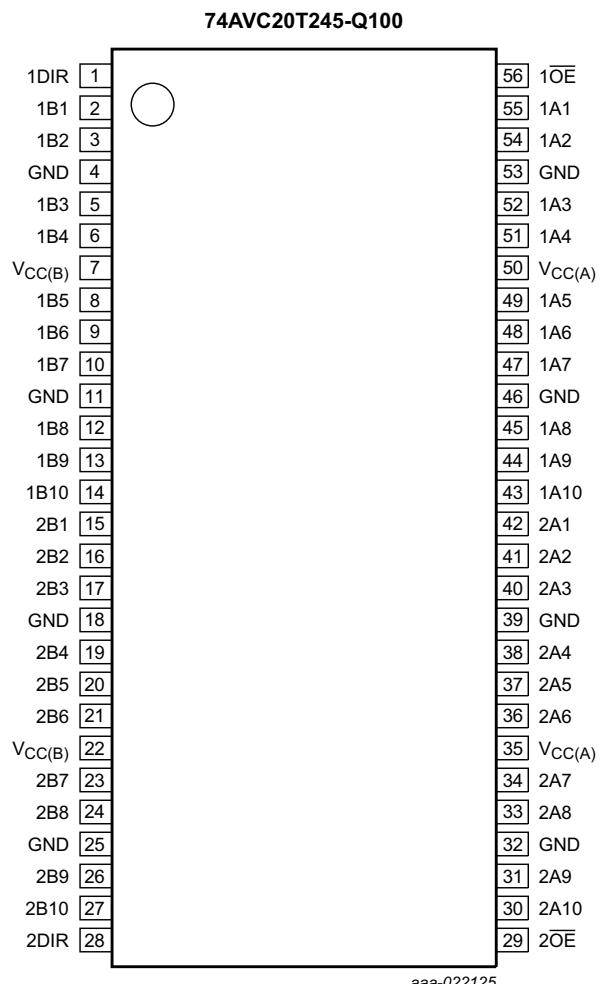


Fig 3. Pin configuration SOT364-1 (TSSOP56)

## 5.2 Pin description

**Table 2.** Pin description

Symbol	Pin	Description
1DIR, 2DIR	1, 28	direction control
1B1 to 1B10	2, 3, 5, 6, 8, 9, 10, 12, 13, 14	data input or output
2B1 to 2B10	15, 16, 17, 19, 20, 21, 23, 24, 26, 27	data input or output
GND <sup>[1]</sup>	4, 11, 18, 25, 32, 39, 46, 53	ground (0 V)
V <sub>CC(B)</sub>	7, 22	supply voltage B (nBn inputs are referenced to V <sub>CC(B)</sub> )
1OE, 2OE	56, 29	output enable input (active LOW)
1A1 to 1A10	55, 54, 52, 51, 49, 48, 47, 45, 44, 43	data input or output
2A1 to 2A10	42, 41, 40, 38, 37, 36, 34, 33, 31, 30	data input or output
V <sub>CC(A)</sub>	35, 50	supply voltage A (nAn, nOE and nDIR inputs are referenced to V <sub>CC(A)</sub> )
n.c.	-	not connected

[1] All GND pins must be connected to ground (0 V).

## 6. Functional description

**Table 3.** Function table<sup>[1]</sup>

Supply voltage	Input		Input/output <sup>[2]</sup>	
V <sub>CC(A)</sub> , V <sub>CC(B)</sub>	nOE <sup>[3]</sup>	nDIR <sup>[3]</sup>	nAn <sup>[3]</sup>	nBn <sup>[3]</sup>
0.8 V to 3.6 V	L	L	nAn = nBn	input
0.8 V to 3.6 V	L	H	input	nBn = nAn
0.8 V to 3.6 V	H	X	Z	Z
GND <sup>[2]</sup>	X	X	Z	Z

[1] H = HIGH voltage level; L = LOW voltage level; X = don't care; Z = high-impedance OFF-state.

[2] If at least one of V<sub>CC(A)</sub> or V<sub>CC(B)</sub> is at GND level, the device goes into suspend mode.

[3] The nAn, nDIR and nOE input circuit is referenced to V<sub>CC(A)</sub>; The nBn input circuit is referenced to V<sub>CC(B)</sub>.

## 7. Limiting values

**Table 4. Limiting values**

In accordance with the Absolute Maximum Rating System (IEC 60134). Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	Min	Max	Unit
V <sub>CC(A)</sub>	supply voltage A		-0.5	+4.6	V
V <sub>CC(B)</sub>	supply voltage B		-0.5	+4.6	V
I <sub>IK</sub>	input clamping current	V <sub>I</sub> < 0 V	-50	-	mA
V <sub>I</sub>	input voltage		[1]	-0.5	+4.6
I <sub>OK</sub>	output clamping current	V <sub>O</sub> < 0 V	-50	-	mA
V <sub>O</sub>	output voltage	Active mode	[1][2][3]	-0.5	V <sub>CCO</sub> + 0.5
		Suspend or 3-state mode	[1]	-0.5	+4.6
I <sub>O</sub>	output current	V <sub>O</sub> = 0 V to V <sub>CCO</sub>	[2]	-	±50
I <sub>CC</sub>	supply current	I <sub>CC(A)</sub> or I <sub>CC(B)</sub>	-	100	mA
I <sub>GND</sub>	ground current		-100	-	mA
T <sub>stg</sub>	storage temperature		-65	+150	°C
P <sub>tot</sub>	total power dissipation	T <sub>amb</sub> = -40 °C to +125 °C			
		TSSOP56 package	[4]	-	600

[1] If the input and output clamping current ratings are observed, the minimum input and minimum output voltage ratings may be exceeded.

[2] V<sub>CCO</sub> is the supply voltage associated with the output port.

[3] V<sub>CCO</sub> + 0.5 V should not exceed 4.6 V.

[4] Above 55 °C, the value of P<sub>tot</sub> derates linearly with 8.0 mW/K.

## 8. Recommended operating conditions

**Table 5. Recommended operating conditions**

Symbol	Parameter	Conditions	Min	Max	Unit
V <sub>CC(A)</sub>	supply voltage A		0.8	3.6	V
V <sub>CC(B)</sub>	supply voltage B		0.8	3.6	V
V <sub>I</sub>	input voltage		0	3.6	V
V <sub>O</sub>	output voltage	Active mode	[1]	0	V <sub>CCO</sub>
		Suspend or 3-state mode		0	3.6
T <sub>amb</sub>	ambient temperature		-40	+125	°C
Δt/ΔV	input transition rise and fall rate	V <sub>CCI</sub> = 0.8 V to 3.6 V	[2]	-	5 ns/V

[1] V<sub>CCO</sub> is the supply voltage associated with the output port.

[2] V<sub>CCI</sub> is the supply voltage associated with the input port.

## 9. Static characteristics

**Table 6. Typical static characteristics at  $T_{amb} = 25^{\circ}\text{C}$** <sup>[1][2]</sup>

At recommended operating conditions; voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	Min	Typ	Max	Unit	
$V_{OH}$	HIGH-level output voltage	$V_I = V_{IH}$ or $V_{IL}$					
		$I_O = -1.5 \text{ mA}$ ; $V_{CC(A)} = V_{CC(B)} = 0.8 \text{ V}$	-	0.69	-	V	
$V_{OL}$	LOW-level output voltage	$V_I = V_{IH}$ or $V_{IL}$					
		$I_O = 1.5 \text{ mA}$ ; $V_{CC(A)} = V_{CC(B)} = 0.8 \text{ V}$	-	0.07	-	V	
$I_I$	input leakage current	nDIR, nOE input; $V_I = 0 \text{ V}$ or $3.6 \text{ V}$ ; $V_{CC(A)} = V_{CC(B)} = 0.8 \text{ V}$ to $3.6 \text{ V}$	-	$\pm 0.025$	$\pm 0.25$	$\mu\text{A}$	
$I_{OZ}$	OFF-state output current	A or B port; $V_O = 0 \text{ V}$ or $V_{CCO}$ ; $V_{CC(A)} = V_{CC(B)} = 3.6 \text{ V}$	[3]	-	$\pm 0.5$	$\pm 2.5$	$\mu\text{A}$
		suspend mode A port; $V_O = 0 \text{ V}$ or $V_{CCO}$ ; $V_{CC(A)} = 3.6 \text{ V}$ ; $V_{CC(B)} = 0 \text{ V}$		-	$\pm 0.5$	$\pm 2.5$	$\mu\text{A}$
		suspend mode B port; $V_O = 0 \text{ V}$ or $V_{CCO}$ ; $V_{CC(A)} = 0 \text{ V}$ ; $V_{CC(B)} = 3.6 \text{ V}$		-	$\pm 0.5$	$\pm 2.5$	$\mu\text{A}$
$I_{OFF}$	power-off leakage current	A port; $V_I$ or $V_O = 0 \text{ V}$ to $3.6 \text{ V}$ ; $V_{CC(A)} = 0 \text{ V}$ ; $V_{CC(B)} = 0.8 \text{ V}$ to $3.6 \text{ V}$	-	$\pm 0.1$	$\pm 1$	$\mu\text{A}$	
		B port; $V_I$ or $V_O = 0 \text{ V}$ to $3.6 \text{ V}$ ; $V_{CC(B)} = 0 \text{ V}$ ; $V_{CC(A)} = 0.8 \text{ V}$ to $3.6 \text{ V}$	-	$\pm 0.1$	$\pm 1$	$\mu\text{A}$	
$C_I$	input capacitance	nDIR, nOE input; $V_I = 0 \text{ V}$ or $3.3 \text{ V}$ ; $V_{CC(A)} = V_{CC(B)} = 3.3 \text{ V}$	-	2.0	-	pF	
$C_{I/O}$	input/output capacitance	A and B port; $V_O = 3.3 \text{ V}$ or $0 \text{ V}$ ; $V_{CC(A)} = V_{CC(B)} = 3.3 \text{ V}$	-	4.0	-	pF	

[1]  $V_{CCO}$  is the supply voltage associated with the output port.

[2]  $V_{CCI}$  is the supply voltage associated with the data input port.

[3] For I/O ports, the parameter  $I_{OZ}$  includes the input leakage current.

**Table 7. Static characteristics**<sup>[1][2]</sup>

At recommended operating conditions; voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	-40 °C to +85 °C		-40 °C to +125 °C		Unit
			Min	Max	Min	Max	
$V_{IH}$	HIGH-level input voltage	data input					
		$V_{CCI} = 0.8 \text{ V}$	0.70 $V_{CCI}$	-	0.70 $V_{CCI}$	-	V
		$V_{CCI} = 1.1 \text{ V}$ to $1.95 \text{ V}$	0.65 $V_{CCI}$	-	0.65 $V_{CCI}$	-	V
		$V_{CCI} = 2.3 \text{ V}$ to $2.7 \text{ V}$	1.6	-	1.6	-	V
		$V_{CCI} = 3.0 \text{ V}$ to $3.6 \text{ V}$	2	-	2	-	V
		nDIR, nOE input					
		$V_{CC(A)} = 0.8 \text{ V}$	0.70 $V_{CC(A)}$	-	0.70 $V_{CC(A)}$	-	V
		$V_{CC(A)} = 1.1 \text{ V}$ to $1.95 \text{ V}$	0.65 $V_{CC(A)}$	-	0.65 $V_{CC(A)}$	-	V
		$V_{CC(A)} = 2.3 \text{ V}$ to $2.7 \text{ V}$	1.6	-	1.6	-	V
		$V_{CC(A)} = 3.0 \text{ V}$ to $3.6 \text{ V}$	2	-	2	-	V

**Table 7.** Static characteristics ...continued<sup>[1][2]</sup>

At recommended operating conditions; voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	−40 °C to +85 °C		−40 °C to +125 °C		Unit	
			Min	Max	Min	Max		
V <sub>IL</sub>	LOW-level input voltage	data input						
		V <sub>CC1</sub> = 0.8 V	-	0.30V <sub>CC1</sub>	-	0.30V <sub>CC1</sub>	V	
		V <sub>CC1</sub> = 1.1 V to 1.95 V	-	0.35V <sub>CC1</sub>	-	0.35V <sub>CC1</sub>	V	
		V <sub>CC1</sub> = 2.3 V to 2.7 V	-	0.7	-	0.7	V	
		V <sub>CC1</sub> = 3.0 V to 3.6 V	-	0.8	-	0.8	V	
		nDIR, nOE input						
		V <sub>CC(A)</sub> = 0.8 V	-	0.30V <sub>CC(A)</sub>	-	0.30V <sub>CC(A)</sub>	V	
		V <sub>CC(A)</sub> = 1.1 V to 1.95 V	-	0.35V <sub>CC(A)</sub>	-	0.35V <sub>CC(A)</sub>	V	
		V <sub>CC(A)</sub> = 2.3 V to 2.7 V	-	0.7	-	0.7	V	
		V <sub>CC(A)</sub> = 3.0 V to 3.6 V	-	0.8	-	0.8	V	
V <sub>OH</sub>	HIGH-level output voltage	V <sub>I</sub> = V <sub>IH</sub> or V <sub>IL</sub>						
		I <sub>O</sub> = −100 μA; V <sub>CC(A)</sub> = V <sub>CC(B)</sub> = 0.8 V to 3.6 V	V <sub>CCO</sub> − 0.1	-	V <sub>CCO</sub> − 0.1	-	V	
		I <sub>O</sub> = −3 mA; V <sub>CC(A)</sub> = V <sub>CC(B)</sub> = 1.1 V	0.85	-	0.85	-	V	
		I <sub>O</sub> = −6 mA; V <sub>CC(A)</sub> = V <sub>CC(B)</sub> = 1.4 V	1.05	-	1.05	-	V	
		I <sub>O</sub> = −8 mA; V <sub>CC(A)</sub> = V <sub>CC(B)</sub> = 1.65 V	1.2	-	1.2	-	V	
		I <sub>O</sub> = −9 mA; V <sub>CC(A)</sub> = V <sub>CC(B)</sub> = 2.3 V	1.75	-	1.75	-	V	
		I <sub>O</sub> = −12 mA; V <sub>CC(A)</sub> = V <sub>CC(B)</sub> = 3.0 V	2.3	-	2.3	-	V	
V <sub>OL</sub>	LOW-level output voltage	V <sub>I</sub> = V <sub>IH</sub> or V <sub>IL</sub>						
		I <sub>O</sub> = 100 μA; V <sub>CC(A)</sub> = V <sub>CC(B)</sub> = 0.8 V to 3.6 V	-	0.1	-	0.1	V	
		I <sub>O</sub> = 3 mA; V <sub>CC(A)</sub> = V <sub>CC(B)</sub> = 1.1 V	-	0.25	-	0.25	V	
		I <sub>O</sub> = 6 mA; V <sub>CC(A)</sub> = V <sub>CC(B)</sub> = 1.4 V	-	0.35	-	0.35	V	
		I <sub>O</sub> = 8 mA; V <sub>CC(A)</sub> = V <sub>CC(B)</sub> = 1.65 V	-	0.45	-	0.45	V	
		I <sub>O</sub> = 9 mA; V <sub>CC(A)</sub> = V <sub>CC(B)</sub> = 2.3 V	-	0.55	-	0.55	V	
		I <sub>O</sub> = 12 mA; V <sub>CC(A)</sub> = V <sub>CC(B)</sub> = 3.0 V	-	0.7	-	0.7	V	
I <sub>I</sub>	input leakage current	nDIR, nOE input; V <sub>I</sub> = 0 V or 3.6 V; V <sub>CC(A)</sub> = V <sub>CC(B)</sub> = 0.8 V to 3.6 V	-	±1	-	±5	μA	
I <sub>OZ</sub>	OFF-state output current	A or B port; V <sub>O</sub> = 0 V or V <sub>CCO</sub> ; V <sub>CC(A)</sub> = V <sub>CC(B)</sub> = 3.6 V	[3]	-	±5	-	±30	μA
		suspend mode A port; V <sub>O</sub> = 0 V or V <sub>CCO</sub> ; V <sub>CC(A)</sub> = 3.6 V; V <sub>CC(B)</sub> = 0 V	[3]	-	±5	-	±30	μA
		suspend mode B port; V <sub>O</sub> = 0 V or V <sub>CCO</sub> ; V <sub>CC(A)</sub> = 0 V; V <sub>CC(B)</sub> = 3.6 V	[3]	-	±5	-	±30	μA

**Table 7.** Static characteristics ...continued<sup>[1][2]</sup>

At recommended operating conditions; voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	-40 °C to +85 °C		-40 °C to +125 °C		Unit
			Min	Max	Min	Max	
I <sub>OFF</sub>	power-off leakage current	A port; V <sub>I</sub> or V <sub>O</sub> = 0 V to 3.6 V; V <sub>CC(A)</sub> = 0 V; V <sub>CC(B)</sub> = 0.8 V to 3.6 V	-	±5	-	±30	µA
		B port; V <sub>I</sub> or V <sub>O</sub> = 0 V to 3.6 V; V <sub>CC(B)</sub> = 0 V; V <sub>CC(A)</sub> = 0.8 V to 3.6 V	-	±5	-	±30	µA
I <sub>CC</sub>	supply current	A port; V <sub>I</sub> = 0 V or V <sub>CCI</sub> ; I <sub>O</sub> = 0 A					
		V <sub>CC(A)</sub> = 0.8 V to 3.6 V; V <sub>CC(B)</sub> = 0.8 V to 3.6 V	-	45	-	190	µA
		V <sub>CC(A)</sub> = 1.1 V to 3.6 V; V <sub>CC(B)</sub> = 1.1 V to 3.6 V	-	35	-	140	µA
		V <sub>CC(A)</sub> = 3.6 V; V <sub>CC(B)</sub> = 0 V	-	35	-	140	µA
		V <sub>CC(A)</sub> = 0 V; V <sub>CC(B)</sub> = 3.6 V	-5	-	-20	-	µA
		B port; V <sub>I</sub> = 0 V or V <sub>CCI</sub> ; I <sub>O</sub> = 0 A					
		V <sub>CC(A)</sub> = 0.8 V to 3.6 V; V <sub>CC(B)</sub> = 0.8 V to 3.6 V	-	45	-	190	µA
		V <sub>CC(A)</sub> = 1.1 V to 3.6 V; V <sub>CC(B)</sub> = 1.1 V to 3.6 V	-	35	-	140	µA
		V <sub>CC(A)</sub> = 3.6 V; V <sub>CC(B)</sub> = 0 V	-5	-	-20	-	µA
		V <sub>CC(A)</sub> = 0 V; V <sub>CC(B)</sub> = 3.6 V	-	35	-	140	µA
		A plus B port (I <sub>CC(A)</sub> + I <sub>CC(B)</sub> ); I <sub>O</sub> = 0 A; V <sub>I</sub> = 0 V or V <sub>CCI</sub> ; V <sub>CC(A)</sub> = 0.8 V to 3.6 V; V <sub>CC(B)</sub> = 0.8 V to 3.6 V	-	80	-	270	µA
		A plus B port (I <sub>CC(A)</sub> + I <sub>CC(B)</sub> ); I <sub>O</sub> = 0 A; V <sub>I</sub> = 0 V or V <sub>CCI</sub> ; V <sub>CC(A)</sub> = 1.1 V to 3.6 V; V <sub>CC(B)</sub> = 1.1 V to 3.6 V	-	65	-	220	µA

[1] V<sub>CCO</sub> is the supply voltage associated with the output port.[2] V<sub>CCI</sub> is the supply voltage associated with the data input port.[3] For I/O ports, the parameter I<sub>OZ</sub> includes the input leakage current.**Table 8.** Typical total supply current (I<sub>CC(A)</sub> + I<sub>CC(B)</sub>)

V <sub>CC(A)</sub>	V <sub>CC(B)</sub>							Unit
	0 V	0.8 V	1.2 V	1.5 V	1.8 V	2.5 V	3.3 V	
0 V	0	0.1	0.1	0.1	0.1	0.1	0.1	µA
0.8 V	0.1	0.1	0.1	0.1	0.1	0.3	1.6	µA
1.2 V	0.1	0.1	0.1	0.1	0.1	0.1	0.8	µA
1.5 V	0.1	0.1	0.1	0.1	0.1	0.1	0.4	µA
1.8 V	0.1	0.1	0.1	0.1	0.1	0.1	0.2	µA
2.5 V	0.1	0.3	0.1	0.1	0.1	0.1	0.1	µA
3.3 V	0.1	1.6	0.8	0.4	0.2	0.1	0.1	µA

## 10. Dynamic characteristics

**Table 9. Typical power dissipation capacitance at  $V_{CC(A)} = V_{CC(B)}$  and  $T_{amb} = 25^\circ C$**  [1][2]

Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	$V_{CC(A)} = V_{CC(B)}$						Unit
			0.8 V	1.2 V	1.5 V	1.8 V	2.5 V	3.3 V	
$C_{PD}$	power dissipation capacitance	A port: (direction A to B); output enabled	0.2	0.2	0.2	0.2	0.3	0.4	pF
		A port: (direction A to B); output disabled	0.2	0.2	0.2	0.2	0.3	0.4	pF
		A port: (direction B to A); output enabled	9.5	9.7	9.8	9.9	10.7	11.9	pF
		A port: (direction B to A); output disabled	0.6	0.6	0.6	0.6	0.7	0.7	pF
		B port: (direction A to B); output enabled	9.5	9.7	9.8	9.9	10.7	11.9	pF
		B port: (direction A to B); output disabled	0.6	0.6	0.6	0.6	0.7	0.7	pF
		B port: (direction B to A); output enabled	0.2	0.2	0.2	0.2	0.3	0.4	pF
		B port: (direction B to A); output disabled	0.2	0.2	0.2	0.2	0.3	0.4	pF

[1]  $C_{PD}$  is used to determine the dynamic power dissipation ( $P_D$  in  $\mu W$ ).

$$P_D = C_{PD} \times V_{CC}^2 \times f_i \times N + \Sigma(C_L \times V_{CC}^2 \times f_o) \text{ where:}$$

$f_i$  = input frequency in MHz;

$f_o$  = output frequency in MHz;

$C_L$  = load capacitance in pF;

$V_{CC}$  = supply voltage in V;

$N$  = number of inputs switching;

$\Sigma(C_L \times V_{CC}^2 \times f_o)$  = sum of the outputs.

[2]  $f_i = 10$  MHz;  $V_I = \text{GND}$  to  $V_{CC}$ ;  $t_r = t_f = 1$  ns;  $C_L = 0$  pF;  $R_L = \infty \Omega$ .

**Table 10. Typical dynamic characteristics at  $V_{CC(A)} = 0.8 \text{ V}$  and  $T_{amb} = 25^\circ\text{C}$**  [1]Voltages are referenced to GND (ground = 0 V); for test circuit, see [Figure 6](#); for wave forms see [Figure 4](#) and [Figure 5](#)

Symbol	Parameter	Conditions	$V_{CC(B)}$						Unit
			0.8 V	1.2 V	1.5 V	1.8 V	2.5 V	3.3 V	
$t_{pd}$	propagation delay	nAn to nBn	14.4	7.0	6.2	6.0	5.9	6.0	ns
		nBn to nAn	14.4	12.4	12.1	11.9	11.8	11.8	ns
$t_{dis}$	disable time	nOE to nAn	16.2	16.2	16.2	16.2	16.2	16.2	ns
		nOE to nBn	17.6	10.0	9.0	9.1	8.7	9.3	ns
$t_{en}$	enable time	nOE to nAn	21.9	21.9	21.9	21.9	21.9	21.9	ns
		nOE to nBn	22.2	11.1	9.8	9.4	9.4	9.6	ns

[1]  $t_{pd}$  is the same as  $t_{PLH}$  and  $t_{PHL}$ ;  $t_{dis}$  is the same as  $t_{PLZ}$  and  $t_{PHZ}$ ;  $t_{en}$  is the same as  $t_{PZL}$  and  $t_{PZH}$ .**Table 11. Typical dynamic characteristics at  $V_{CC(B)} = 0.8 \text{ V}$  and  $T_{amb} = 25^\circ\text{C}$**  [1]Voltages are referenced to GND (ground = 0 V); for test circuit, see [Figure 6](#); for wave forms see [Figure 4](#) and [Figure 5](#)

Symbol	Parameter	Conditions	$V_{CC(A)}$						Unit
			0.8 V	1.2 V	1.5 V	1.8 V	2.5 V	3.3 V	
$t_{pd}$	propagation delay	nAn to nBn	14.4	12.4	12.1	11.9	11.8	11.8	ns
		nBn to nAn	14.4	7.0	6.2	6.0	5.9	6.0	ns
$t_{dis}$	disable time	nOE to nAn	16.2	5.9	4.4	4.2	3.1	3.5	ns
		nOE to nBn	17.6	14.2	13.7	13.6	13.3	13.1	ns
$t_{en}$	enable time	nOE to nAn	21.9	6.4	4.4	3.5	2.6	2.3	ns
		nOE to nBn	22.2	17.7	17.2	17.0	16.8	16.7	ns

[1]  $t_{pd}$  is the same as  $t_{PLH}$  and  $t_{PHL}$ ;  $t_{dis}$  is the same as  $t_{PLZ}$  and  $t_{PHZ}$ ;  $t_{en}$  is the same as  $t_{PZL}$  and  $t_{PZH}$ .

**Table 12. Dynamic characteristics for temperature range –40 °C to +85 °C [1]**Voltages are referenced to GND (ground = 0 V); for test circuit, see [Figure 6](#); for wave forms see [Figure 4](#) and [Figure 5](#).

Symbol	Parameter	Conditions	V <sub>CC(B)</sub>										Unit	
			1.2 V ± 0.1 V		1.5 V ± 0.1 V		1.8 V ± 0.15 V		2.5 V ± 0.2 V		3.3 V ± 0.3 V			
			Min	Max	Min	Max	Min	Max	Min	Max	Min	Max		
<b>V<sub>CC(A)</sub> = 1.1 V to 1.3 V</b>														
t <sub>pd</sub>	propagation delay	nAn to nBn	0.5	9.4	0.5	7.1	0.5	6.2	0.5	5.2	0.5	5.1	ns	
		nBn to nAn	0.5	9.4	0.5	8.9	0.5	8.7	0.5	8.4	0.5	8.2	ns	
t <sub>dis</sub>	disable time	nOE to nAn	2.0	11.9	2.0	11.9	2.0	11.9	2.0	11.9	2.0	11.9	ns	
		nOE to nBn	1.5	12.7	1.5	9.8	1.5	9.6	1.0	8.1	1.0	9.0	ns	
t <sub>en</sub>	enable time	nOE to nAn	1.5	15.3	1.5	15.3	1.5	15.3	1.5	15.3	1.5	15.3	ns	
		nOE to nBn	1.0	15.6	1.0	11.5	1.0	10.0	0.5	8.4	0.5	8.0	ns	
<b>V<sub>CC(A)</sub> = 1.4 V to 1.6 V</b>														
t <sub>pd</sub>	propagation delay	nAn to nBn	0.5	8.9	0.5	6.4	0.5	5.4	0.5	4.3	0.5	3.9	ns	
		nBn to nAn	0.5	7.1	0.5	6.4	0.5	6.1	0.5	5.8	0.5	5.7	ns	
t <sub>dis</sub>	disable time	nOE to nAn	2.0	9.0	2.0	9.0	2.0	9.0	2.0	9.0	2.0	9.0	ns	
		nOE to nBn	1.5	11.7	1.5	9.0	1.5	7.8	1.0	6.4	1.0	6.0	ns	
t <sub>en</sub>	enable time	nOE to nAn	1.5	10.3	1.5	10.3	1.5	10.3	1.5	10.2	1.5	10.2	ns	
		nOE to nBn	1.0	14.3	1.0	10.3	1.0	8.4	0.5	6.1	0.5	5.3	ns	
<b>V<sub>CC(A)</sub> = 1.65 V to 1.95 V</b>														
t <sub>pd</sub>	propagation delay	nAn to nBn	0.5	8.7	0.5	6.1	0.5	5.0	0.5	3.9	0.5	3.5	ns	
		nBn to nAn	0.5	6.2	0.5	5.4	0.5	5.0	0.5	4.7	0.5	4.6	ns	
t <sub>dis</sub>	disable time	nOE to nAn	2.0	7.4	2.0	7.4	2.0	7.4	2.0	7.4	2.0	7.4	ns	
		nOE to nBn	1.5	11.3	1.5	8.7	1.5	7.4	1.0	5.8	1.0	5.6	ns	
t <sub>en</sub>	enable time	nOE to nAn	1.0	8.1	1.0	8.1	1.0	7.9	1.0	7.9	1.0	7.9	ns	
		nOE to nBn	0.5	13.8	0.5	10.0	0.5	7.9	0.5	5.7	0.5	4.8	ns	
<b>V<sub>CC(A)</sub> = 2.3 V to 2.7 V</b>														
t <sub>pd</sub>	propagation delay	nAn to nBn	0.5	8.4	0.5	5.8	0.5	4.7	0.5	3.5	0.5	3.0	ns	
		nBn to nAn	0.5	5.2	0.5	4.3	0.5	3.9	0.5	3.5	0.5	3.4	ns	
t <sub>dis</sub>	disable time	nOE to nAn	1.1	5.2	1.1	5.2	1.1	5.2	1.1	5.2	1.1	5.2	ns	
		nOE to nBn	1.2	10.8	1.2	8.2	1.2	6.9	1.0	5.3	1.0	5.2	ns	
t <sub>en</sub>	enable time	nOE to nAn	0.5	5.4	0.5	5.4	0.5	5.3	0.5	5.2	0.5	5.2	ns	
		nOE to nBn	0.5	13.3	0.5	9.6	0.5	7.6	0.5	5.3	0.5	4.3	ns	
<b>V<sub>CC(A)</sub> = 3.0 V to 3.6 V</b>														
t <sub>pd</sub>	propagation delay	nAn to nBn	0.5	8.2	0.5	5.7	0.5	4.6	0.5	3.4	0.5	2.9	ns	
		nBn to nAn	0.5	5.1	0.5	3.9	0.5	3.5	0.5	3.0	0.5	2.9	ns	
t <sub>dis</sub>	disable time	nOE to nAn	0.8	5.0	0.8	5.0	0.8	5.0	0.8	5.0	0.8	5.0	ns	
		nOE to nBn	1.2	10.5	1.2	8.1	1.2	6.7	1.0	5.1	0.8	5.0	ns	
t <sub>en</sub>	enable time	nOE to nAn	0.5	4.4	0.5	4.4	0.5	4.3	0.5	4.2	0.5	4.1	ns	
		nOE to nBn	1.0	13.1	1.0	9.6	0.5	7.5	0.5	5.1	0.5	4.1	ns	

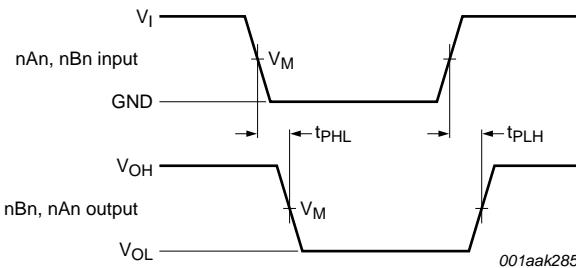
[1] t<sub>pd</sub> is the same as t<sub>PLH</sub> and t<sub>PHL</sub>; t<sub>dis</sub> is the same as t<sub>PLZ</sub> and t<sub>PHZ</sub>; t<sub>en</sub> is the same as t<sub>PZL</sub> and t<sub>PZH</sub>.

**Table 13. Dynamic characteristics for temperature range –40 °C to +125 °C [1]**Voltages are referenced to GND (ground = 0 V); for test circuit, see [Figure 6](#); for wave forms see [Figure 4](#) and [Figure 5](#)

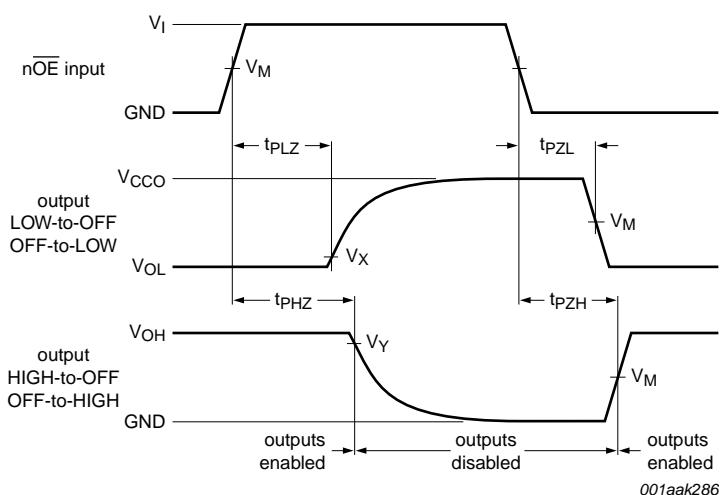
Symbol	Parameter	Conditions	V <sub>CC(B)</sub>										Unit	
			1.2 V ± 0.1 V		1.5 V ± 0.1 V		1.8 V ± 0.15 V		2.5 V ± 0.2 V		3.3 V ± 0.3 V			
			Min	Max	Min	Max	Min	Max	Min	Max	Min	Max		
<b>V<sub>CC(A)</sub> = 1.1 V to 1.3 V</b>														
t <sub>pd</sub>	propagation delay	nAn to nBn	0.5	10.4	0.5	7.9	0.5	6.9	0.5	5.8	0.5	5.7	ns	
		nBn to nAn	0.5	10.4	0.5	9.8	0.5	9.6	0.5	9.3	0.5	9.1	ns	
t <sub>dis</sub>	disable time	nOE to nAn	2.0	13.1	2.0	13.1	2.0	13.1	2.0	13.1	2.0	13.1	ns	
		nOE to nBn	1.5	14.0	1.5	10.8	1.5	10.6	1.0	9.0	1.0	9.9	ns	
t <sub>en</sub>	enable time	nOE to nAn	1.5	16.9	1.5	16.9	1.5	16.9	1.5	16.9	1.5	16.9	ns	
		nOE to nBn	1.0	17.2	1.0	12.7	1.0	11.0	0.5	9.3	0.5	8.8	ns	
<b>V<sub>CC(A)</sub> = 1.4 V to 1.6 V</b>														
t <sub>pd</sub>	propagation delay	nAn to nBn	0.5	9.8	0.5	7.1	0.5	6.0	0.5	4.8	0.5	4.3	ns	
		nBn to nAn	0.5	7.9	0.5	7.1	0.5	6.8	0.5	6.4	0.5	6.3	ns	
t <sub>dis</sub>	disable time	nOE to nAn	2.0	9.9	2.0	9.9	2.0	9.9	2.0	9.9	2.0	9.9	ns	
		nOE to nBn	1.5	12.9	1.5	9.9	1.5	8.6	1.0	7.1	1.0	6.6	ns	
t <sub>en</sub>	enable time	nOE to nAn	1.5	11.4	1.5	11.4	1.5	11.4	1.5	11.3	1.5	11.3	ns	
		nOE to nBn	1.0	15.8	1.0	11.4	1.0	9.3	0.5	6.8	0.5	5.9	ns	
<b>V<sub>CC(A)</sub> = 1.65 V to 1.95 V</b>														
t <sub>pd</sub>	propagation delay	nAn to nBn	0.5	9.6	0.5	6.8	0.5	5.5	0.5	4.3	0.5	3.9	ns	
		nBn to nAn	0.5	6.9	0.5	6.0	0.5	5.5	0.5	5.2	0.5	5.1	ns	
t <sub>dis</sub>	disable time	nOE to nAn	2.0	8.2	2.0	8.2	2.0	8.2	2.0	8.2	2.0	8.2	ns	
		nOE to nBn	1.5	12.5	1.5	9.6	1.5	8.2	1.0	6.4	1.0	6.2	ns	
t <sub>en</sub>	enable time	nOE to nAn	1.0	9.0	1.0	9.0	1.0	8.7	1.0	8.7	1.0	8.7	ns	
		nOE to nBn	0.5	15.2	0.5	11.0	0.5	8.7	0.5	6.3	0.5	5.3	ns	
<b>V<sub>CC(A)</sub> = 2.3 V to 2.7 V</b>														
t <sub>pd</sub>	propagation delay	nAn to nBn	0.5	9.3	0.5	6.4	0.5	5.2	0.5	3.9	0.5	3.3	ns	
		nBn to nAn	0.5	5.8	0.5	4.8	0.5	4.3	0.5	3.9	0.5	3.8	ns	
t <sub>dis</sub>	disable time	nOE to nAn	1.1	5.8	1.1	5.8	1.1	5.8	1.1	5.8	1.1	5.8	ns	
		nOE to nBn	1.2	11.9	1.2	9.1	1.2	7.6	1.0	5.9	1.0	5.8	ns	
t <sub>en</sub>	enable time	nOE to nAn	0.5	6.0	0.5	6.0	0.5	5.9	0.5	5.8	0.5	5.8	ns	
		nOE to nBn	0.5	14.7	0.5	10.6	0.5	8.4	0.5	5.9	0.5	4.8	ns	
<b>V<sub>CC(A)</sub> = 3.0 V to 3.6 V</b>														
t <sub>pd</sub>	propagation delay	nAn to nBn	0.5	9.1	0.5	6.3	0.5	5.1	0.5	3.8	0.5	3.2	ns	
		nBn to nAn	0.5	5.7	0.5	4.3	0.5	3.9	0.5	3.3	0.5	3.2	ns	
t <sub>dis</sub>	disable time	nOE to nAn	0.8	5.5	0.8	5.5	0.8	5.5	0.8	5.5	0.8	5.5	ns	
		nOE to nBn	1.2	11.6	1.2	9.0	1.2	7.4	1.0	5.7	0.8	5.5	ns	
t <sub>en</sub>	enable time	nOE to nAn	0.5	4.9	0.5	4.9	0.5	4.8	0.5	4.7	0.5	4.6	ns	
		nOE to nBn	1.0	14.5	1.0	10.6	0.5	8.3	0.5	5.7	0.5	4.6	ns	

[1] t<sub>pd</sub> is the same as t<sub>PLH</sub> and t<sub>PHL</sub>; t<sub>dis</sub> is the same as t<sub>PLZ</sub> and t<sub>PHZ</sub>; t<sub>en</sub> is the same as t<sub>PZL</sub> and t<sub>PZH</sub>.

## 11. Waveforms



**Fig 4. The data input (nAn, nBn) to output (nBn, nAn) propagation delay times**



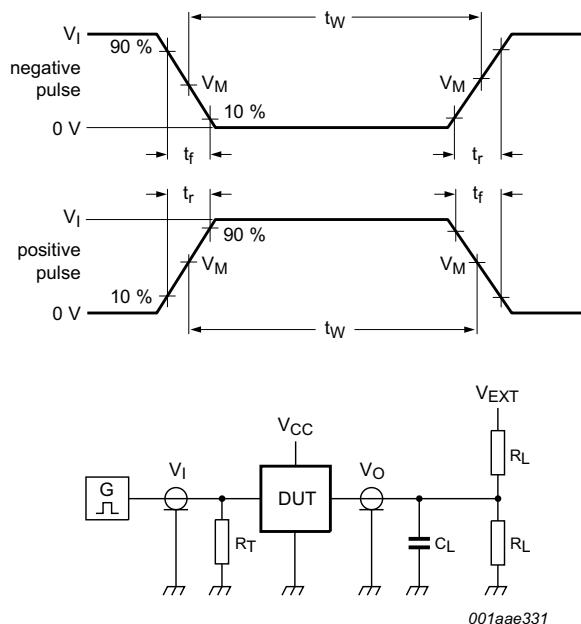
**Fig 5. Enable and disable times**

**Table 14. Measurement points**

Supply voltage	Input <sup>[1]</sup>	Output <sup>[2]</sup>		
$V_{CC(A)}$ , $V_{CC(B)}$	$V_M$	$V_M$	$V_X$	$V_Y$
0.8 V to 1.6 V	$0.5V_{CCI}$	$0.5V_{CCO}$	$V_{OL} + 0.1$ V	$V_{OH} - 0.1$ V
1.65 V to 2.7 V	$0.5V_{CCI}$	$0.5V_{CCO}$	$V_{OL} + 0.15$ V	$V_{OH} - 0.15$ V
3.0 V to 3.6 V	$0.5V_{CCI}$	$0.5V_{CCO}$	$V_{OL} + 0.3$ V	$V_{OH} - 0.3$ V

[1]  $V_{CCI}$  is the supply voltage associated with the data input port.

[2]  $V_{CCO}$  is the supply voltage associated with the output port.



Test data is given in [Table 15](#).

$R_L$  = Load resistance.

$C_L$  = Load capacitance including jig and probe capacitance.

$R_T$  = Termination resistance.

$V_{EXT}$  = External voltage for measuring switching times.

**Fig 6. Test circuit for measuring switching times**

**Table 15. Test data**

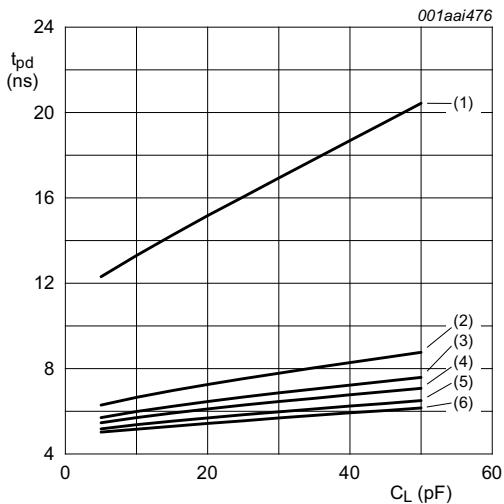
Supply voltage	Input		Load		$V_{EXT}$		
$V_{CC(A)}$ , $V_{CC(B)}$	$V_I^{[1]}$	$\Delta t/\Delta V^{[2]}$	$C_L$	$R_L$	$t_{PLH}$ , $t_{PHL}$	$t_{PZH}$ , $t_{PHZ}$	$t_{PZL}$ , $t_{PLZ}^{[3]}$
0.8 V to 1.6 V	$V_{CCI}$	$\leq 1.0 \text{ ns/V}$	15 pF	2 k $\Omega$	open	GND	$2V_{CCO}$
1.65 V to 2.7 V	$V_{CCI}$	$\leq 1.0 \text{ ns/V}$	15 pF	2 k $\Omega$	open	GND	$2V_{CCO}$
3.0 V to 3.6 V	$V_{CCI}$	$\leq 1.0 \text{ ns/V}$	15 pF	2 k $\Omega$	open	GND	$2V_{CCO}$

[1]  $V_{CCI}$  is the supply voltage associated with the data input port.

[2]  $dV/dt \geq 1.0 \text{ V/ns}$

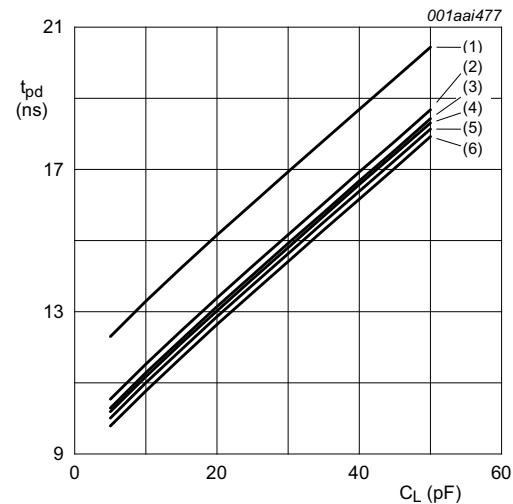
[3]  $V_{CCO}$  is the supply voltage associated with the output port.

## 12. Typical propagation delay characteristics



a. Propagation delay ( $nAn$  to  $nBn$ );  $V_{CC(A)} = 0.8$  V

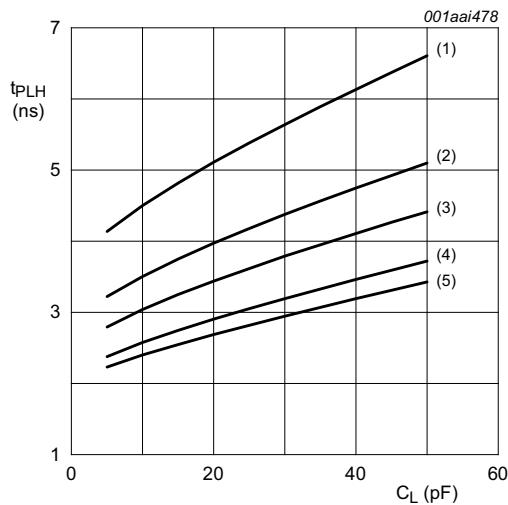
- (1)  $V_{CC(B)} = 0.8$  V.
- (2)  $V_{CC(B)} = 1.2$  V.
- (3)  $V_{CC(B)} = 1.5$  V.
- (4)  $V_{CC(B)} = 1.8$  V.
- (5)  $V_{CC(B)} = 2.5$  V.
- (6)  $V_{CC(B)} = 3.3$  V.



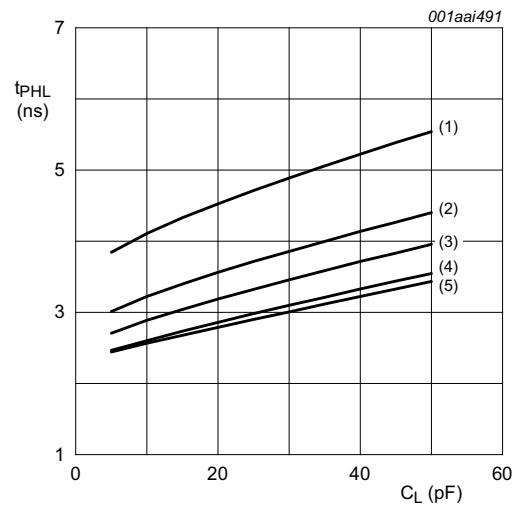
b. Propagation delay ( $nAn$  to  $nBn$ );  $V_{CC(B)} = 0.8$  V

- (1)  $V_{CC(A)} = 0.8$  V.
- (2)  $V_{CC(A)} = 1.2$  V.
- (3)  $V_{CC(A)} = 1.5$  V.
- (4)  $V_{CC(A)} = 1.8$  V.
- (5)  $V_{CC(A)} = 2.5$  V.
- (6)  $V_{CC(A)} = 3.3$  V.

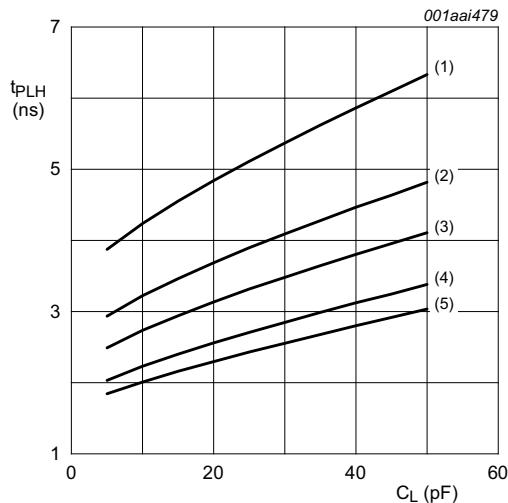
Fig 7. Typical propagation delay versus load capacitance;  $T_{amb} = 25$  °C



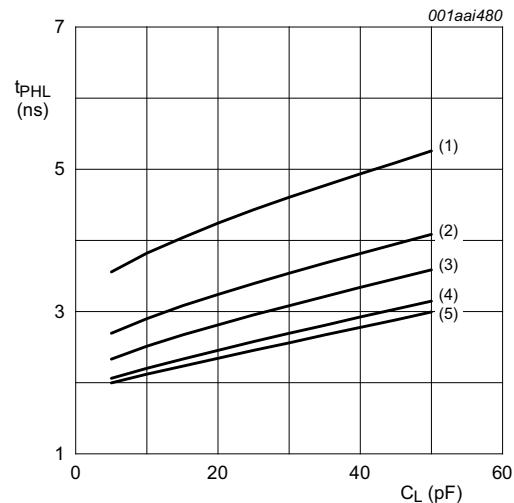
- a. LOW to HIGH propagation delay (nAn to nBn);  
 $V_{CC(A)} = 1.2$  V



- b. HIGH to LOW propagation delay (nAn to nBn);  
 $V_{CC(A)} = 1.2$  V



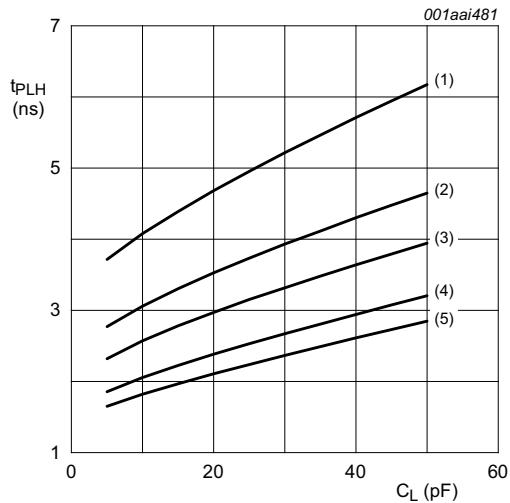
- c. LOW to HIGH propagation delay (nAn to nBn);  
 $V_{CC(A)} = 1.5$  V



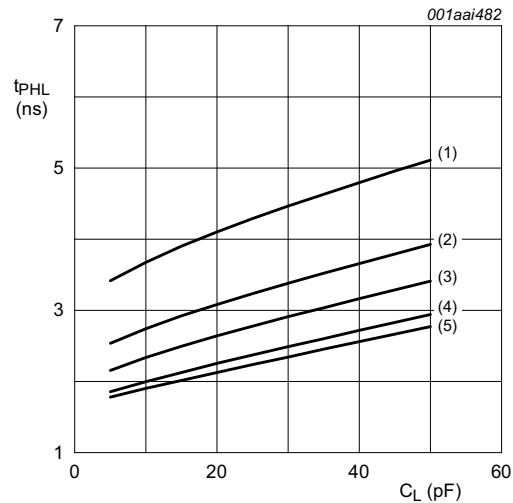
- d. HIGH to LOW propagation delay (nAn to nBn);  
 $V_{CC(A)} = 1.5$  V

- (1)  $V_{CC(B)} = 1.2$  V.
- (2)  $V_{CC(B)} = 1.5$  V.
- (3)  $V_{CC(B)} = 1.8$  V.
- (4)  $V_{CC(B)} = 2.5$  V.
- (5)  $V_{CC(B)} = 3.3$  V.

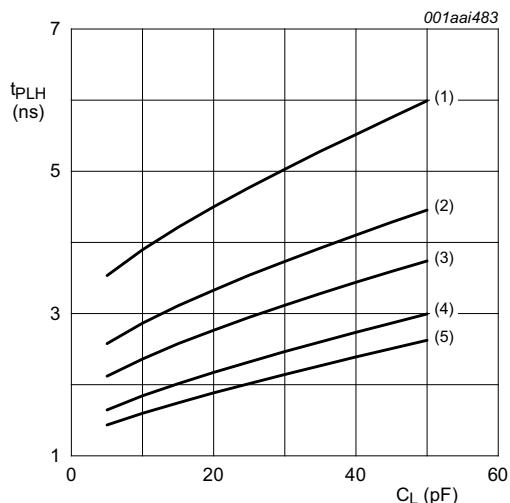
Fig 8. Typical propagation delay versus load capacitance;  $T_{amb} = 25$  °C



- a. LOW to HIGH propagation delay (nAn to nBn);  
V<sub>CC(A)</sub> = 1.8 V

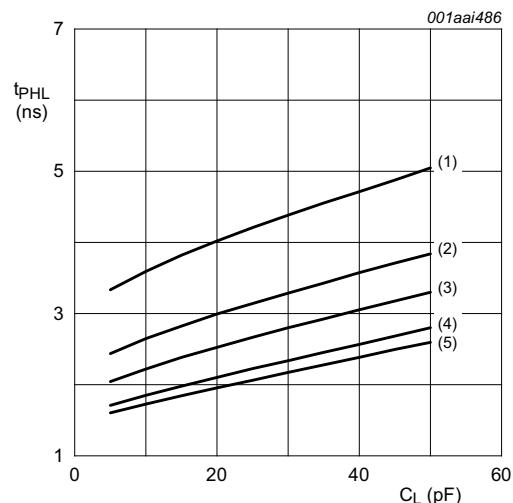


- b. HIGH to LOW propagation delay (nAn to nBn);  
V<sub>CC(A)</sub> = 1.8 V



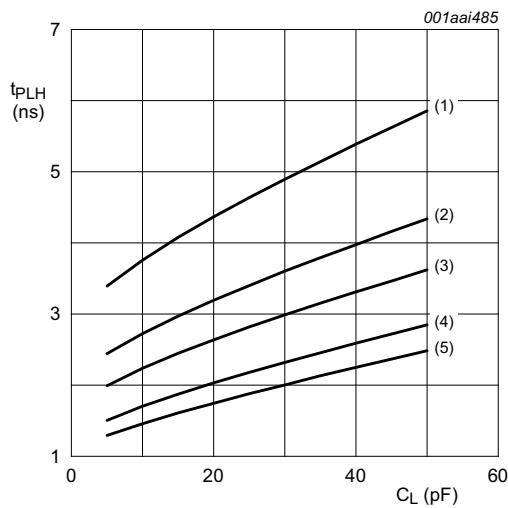
- c. LOW to HIGH propagation delay (nAn to nBn);  
V<sub>CC(A)</sub> = 2.5 V

- (1) V<sub>CC(B)</sub> = 1.2 V.
- (2) V<sub>CC(B)</sub> = 1.5 V.
- (3) V<sub>CC(B)</sub> = 1.8 V.
- (4) V<sub>CC(B)</sub> = 2.5 V.
- (5) V<sub>CC(B)</sub> = 3.3 V.



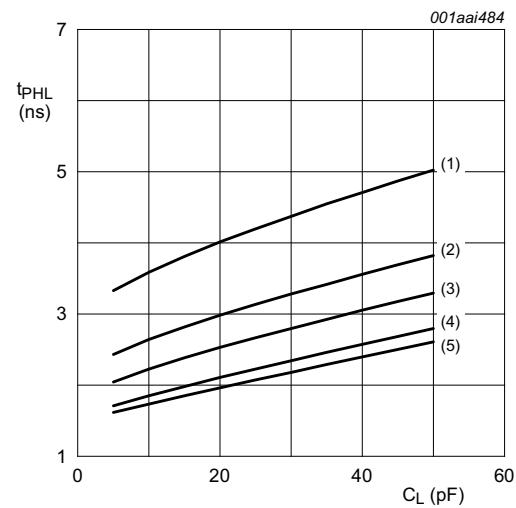
- d. HIGH to LOW propagation delay (nAn to nBn);  
V<sub>CC(A)</sub> = 2.5 V

Fig 9. Typical propagation delay versus load capacitance; T<sub>amb</sub> = 25 °C



- a. LOW to HIGH propagation delay (nAn to nBn);  
 $V_{CC(A)} = 3.3$  V

- (1)  $V_{CC(B)} = 1.2$  V.
- (2)  $V_{CC(B)} = 1.5$  V.
- (3)  $V_{CC(B)} = 1.8$  V.
- (4)  $V_{CC(B)} = 2.5$  V.
- (5)  $V_{CC(B)} = 3.3$  V.



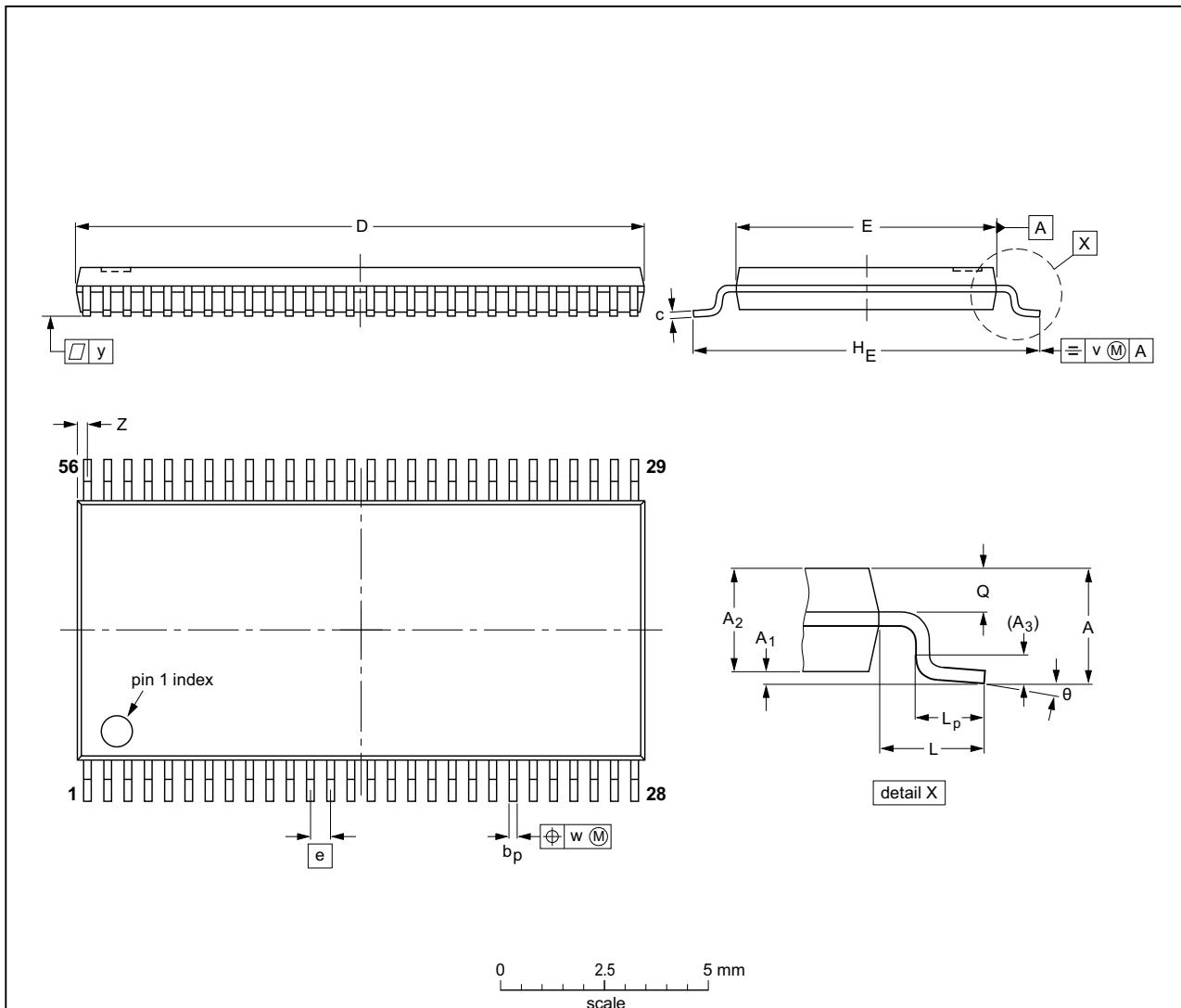
- b. HIGH to LOW propagation delay (nAn to nBn);  
 $V_{CC(A)} = 3.3$  V

Fig 10. Typical propagation delay versus load capacitance;  $T_{amb} = 25$  °C

## 13. Package outline

TSSOP56: plastic thin shrink small outline package; 56 leads; body width 6.1 mm

SOT364-1



### DIMENSIONS (mm are the original dimensions).

UNIT	A max.	A <sub>1</sub>	A <sub>2</sub>	A <sub>3</sub>	b <sub>p</sub>	c	D <sup>(1)</sup>	E <sup>(2)</sup>	e	H <sub>E</sub>	L	L <sub>p</sub>	Q	v	w	y	z	θ
mm	1.2 0.05	0.15 0.85	1.05	0.25	0.28 0.17	0.2 0.1	14.1 13.9	6.2 6.0	0.5	8.3 7.9	1	0.8 0.4	0.50 0.35	0.25	0.08	0.1	0.5 0.1	8° 0°

### Notes

- Plastic or metal protrusions of 0.15 mm maximum per side are not included.
- Plastic interlead protrusions of 0.25 mm maximum per side are not included.

OUTLINE VERSION	REFERENCES			EUROPEAN PROJECTION	ISSUE DATE
	IEC	JEDEC	JEITA		
SOT364-1		MO-153			-99-12-27 03-02-19

Fig 11. Package outline SOT364-1 (TSSOP56)

## 14. Abbreviations

**Table 16. Abbreviations**

Acronym	Description
CDM	Charged Device Model
DUT	Device Under Test
ESD	ElectroStatic Discharge
HBM	Human Body Model
MM	Machine Model
MIL	Military

## 15. Revision history

**Table 17. Revision history**

Document ID	Release date	Data sheet status	Change notice	Supersedes
74AVC20T245_Q100 v.1	20160407	Product data sheet	-	-

## 16. Legal information

### 16.1 Data sheet status

Document status <sup>[1][2]</sup>	Product status <sup>[3]</sup>	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

[1] Please consult the most recently issued document before initiating or completing a design.

[2] The term 'short data sheet' is explained in section "Definitions".

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Date of release: 7 April 2016

Document identifier: 74AVC20T245\_Q100